The 22nd Asian Test Symposium (ATS'13)

Yilan, Taiwan, 18-21 Nov. 2013

http://bug.ee.ntu.edu.tw/ATS2013

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Call For Participation

Early bird discount by Oct. 25, 2013

The Asian Test Symposium (ATS) provides an open forum for researchers and industrial practitioners from all countries of the world, especially from Asia, to exchange innovative ideas on system, board, and device testing with design, manufacturing and field consideration in mind.

Keynote

Test Data Analytics - from Mathematical Tools to Applications

Kwang-Ting (Tim) Cheng, University of California, Santa Barbara

Invited Speeches

New Approaches to Improving Quality and Accelerating Yield Ramp to Meet Process Technology Disruptions

Wu-Tung Cheng, Chief Scientist and Test Research Director, Mentor Graphics

Wide I/O and 3D-IC Testing (tentative)

William Wu Shen, Design Methodology Division, TSMC Ltd

Full-Day and Embedded Tutorials

Statistical Adaptive Tet Methods Targeting "Zero Defect" IC Quality and Reliability

Adit D. Singh, Auburn University

Testing TSV-Based 3D Stacked ICs

Krishnendu Chakrabarty, Duke University

Data Mining in Test - Principles and Practices

Li-C Wang, University of California, Santa Barbara

Software Testing

Farn Wang, National Taiwan University

Vendor Session: New Test Technologies & Roadmap

Janusz Rajski, Mentor Graphics
Andy Hughes, Cadence